



Risk Management Readout Electronics



Risk Overview



WBS		Risk ID			Expires	Title	Rank
6.2.2 Readout Electronics	I hreat	RD-06-02-02- 001	Active	17-Oct- 17		HV Mux does not converge' need to resort to making choices based on available cabling.	40
6.2.2 Readout Electronics	I hreat	RD-06-02-02- 002	Active	17-Oct- 17	27-May-20	Chip run fails or radiation effects cause concern for readout at high rate and we need to do another run.	210
6.2.2 Readout Electronics	I hreat	RD-06-02-02- 003	Active	17-Oct- 17	27-May-20	Chip set not compatible with lpGBT which won't be ready until just before or after production wafer orders for HCC are placed.	140
6.2.2 Readout Electronics	Inreat	RD-06-02-02- 004	Active	27-Feb- 19	1-Sep-20	bPOL12V regulator is delayed	90
6.2.2 Readout Electronics	I hreat	RD-06-02-02- 005	Active	27-Feb- 19	1-Sep-20	Loss of key personnel	60



Highest risk



WBS	6.2.2	Type Th	nreat	Risk ID	RD-0	06-02-02	2-002							
Status	Active													
Expires	27-May-20													
	Chip run fail	ls or radiati	ion effe	cts cause	conc	ern for r	eadout	at high	rate and	d we need	t			
Title	to do anothe	er run.												
Summary	Everything e nearly 1 year	•		•					oth elect	rical and	rad	liation. Chip itera	ations can take	3
Owner		C. Ha	ber						_					
Probability	Pre	40%	Post	25%										
Cost	Lo	550k	Hi	705k										
Schedule	Lo	9 months	Hi	15 mont	ths									
Tech Impact	3 (H)		•			-								
Post Mitg Prob	5 (M)													
Impact Score	Cost	3 (H)	Sched	3 (H)		Rank=	210							
Mitigation	A thorough production including irra	_	chip pe	erforman	ce sim	nulation	during (design p	ohase, AS	SIC design	ı re	view, and post-fa	brication testin	ng,
Response	Determine c experienced		•	_			and its	perforr	mance si	mulations	s, re	evise design, revi	ew with panel	of
Comments*	There are model of 9-15 mon layout, compost impact and variable other production determination impact could	any scenari ths include piler issue 1 would be e cost deper ction activition and asse d range from AMAC. Firs	ios whees the following the following of the second ties caused on \$550 st tasks	ere the chollowing: on this; revious to fix number using projequence k (for desagree)	ip ma detection the part of we ect with the in the	y need to the transports y experts roblem (afers need ide delay project, bor and	o be refected post 1 mon \$200k of the column	abricate roblem th; revidesign) : \$2.852 estimate ald lose ion only	ed even to 2 - 4 modes is ed fabricand extraction was been was been was been was been was been to ha extraction was to ha extraction was to present to ha extraction was been extraction was been extractionally in the extraction was been extracted as the extraction was a subject to the extraction was a s	though it onths; det ication 3-a cost of integral of the ication after). This ue to time of a year was production	is r terr 4 m refa s pr e so wor	ems or failures fromostly functional mine cause 1 more nonths; wafer testabrications (\$325 roblem also propagales associated with of labor time. HCC/AMAC, since	I. Schedule importh; revise circleting 1 month. It for a new magates into the with the root conforthe production.	pact cuit, The ask, e cause ost ction
Tasks Effected*	RE310335M	, RE320650	M											



2nd Highest risk



WBS	6.2.2	Type Th	reat	Risk ID	RD-0	06-02-02-003				
Status	Active					_				
Expires	27-May-20									_
Title	Chip set not co	•	•			be ready until just	befo	re or after		
Summary	The lpGBT sites	on the end-	of-stav	e and cor	nmun	icates with the ou	tside	world. HCC	C ties dire	ectly to lpGBT
Owner		C. Habe	er							
Probability	Pre	20%	Post	10%						
Cost	Lo	510k	Hi	635k						
Schedule	Lo	6 months	Hi	15 mont	ths					
Tech Impact	3 (H)					-				
Post Mitg Prob	3 (L)					_				
Impact Score	Cost	3 (H)	Sched	3 (H)		Rank= 140				
IIV/IITIGATION	be fully explore problem or tha partially reliable	ed to determ t a new subr e communic	ine the nission ations.	e level of one of one of an HCC The HCC	omm C is re will re	unication robustno equired. It is unlike etain a 320Mbps d	ess. It ely tha ata ra	t may be that stave or the in additi	nat EOS c endcap ion to the	bps and multi-drop conditions should omponents are able to mitigate the prototyping will be halted due to e default of 640Mbps.
Response						 continued testing element correction 				ne lowest cost mitigation that HCC ASIC.
Comments*	being designed ability. The rist effects on the sproduction ordwafers and extrother production determination a	by CERN Mik of total fail tave building er release for a labor on the on activities and assembl	croeled lure is I g, Sche r HCCS he LVD causing ly sequ	ctronics and ow, but the dule delay star. If a restrict of the groject we have in the constance in the const	nd in onere mand in one mere mandered m	collaboration with nay be some reliable timated from a won ission of the proof and testing is estimation, we could lose	other oility is orking duction imate that e that e up to	r institution ssues that solution b on HCC is re ed at \$50k- t, due to ti o half a yea	ns with p need wo eeing four equired, t \$150k. T ime scale ar worth	eir design frequency. The IpGBT is roven communications circuit design rk. This would cause downstream nd within 6-15 months of the the cost is \$460k for mask set and his problem also propagates into the es associated with the root cause of labor time. First task affected is the ed by the rest of the project.
Tasks Effected*					,	- p - 3 - 3 - 3 - 3 - 3 - 3 - 3 - 3 - 3	1		- 4	,
TUSKS LITECTED	IVEDETOOUN				A C 1 11	1110 DOE 100 /00 3	1 1 4		5.11	



3rd Highest risk



WBS	6.2.2	Type T	hreat	Risk ID	RD-C	06-02-02-0	004									
Status	Active							-								
Expires	1-Sep-20)														
Title	bPOL12V	/ regulator is	delayed	k												
Summary		is a CERN del the final sup				-	•		-	_			l has s	ome un	certainti	ies
Owner		C. H	•				<u> </u>		<u></u>		-,	,				
Probability	Pre	25%	Post	25%												
Cost	Lo	4k	Hi	18k												
Schedule	Lo	1 month	Hi	6 month	1											
Tech Impact	2 (M)		'	•												
Post Mitg Prob	5 (M)															
Impact Score	Cost	1 (L)	Sched	2 (M)		Rank=	90									
Mitigation	There is r	no mitigation	•													
Response		This would delay the assembly and distribution of power boards which would in turn delay module assembly. Hopefully we could avoid the standing army problem since it is due to be delivered well in advance.														
Comments*	low since	This would delay the assembly and distribution of power boards which would in turn delay module assembly. Cost impact is low since chips should be delivered at least 6 months ahead of start of production. First task affected is loading of production boards Batch 1.														
Tasks Effected	RE261410	0														



4th Highest risk



WBS	6.2.2	Type T	hreat	Risk ID	RD-06-02-02	2-005]				
Status	Active						_				
Expires	1-Sep-20	0									
Title	Loss of k	ey personnel									
Summary		out electronic ts/engineer at		=		enginee	ring tea	am at Pe	nn for the	ASICs and a team of	
Owner		C. Ha	ber								
Probability	Pre	10%	Post	10%							
Cost	Lo	4k	Hi	32k							
Schedule	Lo	1 month	Hi	9 month	IS						
Tech Impact	3 (H)										
Post Mitg Prob	3 (L)										
Impact Score	Cost	1 (L)	Sched	2 (M)	Rank=	60					
Mitigation	There is	no mitigation									
Response	A positio	n would be po	sted a	nd a new l	nire made. In	the inter	im the	existing	staff woul	ld assume additional responsibility	
Comments*		These are long term employees of the institutions with a strong commitment to the project. First tasks affected are design revisions after Jan 2019 in ABC, HCC, AMAC design, and powerboard and HV-Mux.									
Tasks Effected*	RE14036	0, RE260820,	RE3102	260, RE32	0470,RE35051	.0					



Retired Risk



WBS	6.2.2	Type T	hreat	Risk ID	RD-06-02-02	-001	· ·
Status	Active						
Expires	1-May-19						
	HV Mux do	es not conv	erge an	d we nee	d to resort to	making ch	noices based on available
Title	cabling.						
Summary	•		•		•	We are s	till doing a technology selectiion and the parts are boutique.
Summary	While prom	ising we co	uld end	l up with	no solution		
Owner		C. Ha	ber	1			
Probability	Pre	40%	Post	10%			
Cost	Lo	2k	Hi	150k			
Schedule	Lo	0.5 month	Hi	3 month	ıs		
Tech Impact	1 (L)						
Post Mitg Prob	3 (L)						
Impact Score	Cost	1 (L)	Sched	1 (L)	Rank=	40	
Mitigation				-			us the resources on the most promising solution and maximize ation is being pursued to validate the technical performance.
Response	If the techn	ology fails v	ve can	use extra	lines on the st	ave bus t	ape to supply the additional HV lines.
	The technol	logy is nove	l and m	ay not be	commercially	available (e in the un-packaged form we need in the experiment. If it fails
		•	_	_			n the strip modules. As a last ditch solution, to preserve the
Comments	schedule, w	e might bu	ild som	e staves v	v/o HV Mux w	hile conti	nuing to work on the HV Mux solution. Maximum cost is due
	to a 1 year e	engineering	delay.	First task	affected is lon	g term re	liability tests.
Tasks Effected	RE140180						

HV Mux review in March 2019: works and plan to use on detector.